Modeling of Rolling-Web AP-PECVD Reactors

Petr Hotmar, Hubert Caquineau, Nicolas Gherardi

Materials and Plasma Processes, LABORATOIRE PLASMA ET CONVERSION D'ENERGIE, Toulouse

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1/25

Outline



2 Reactor Description

3 Optimization of Confinement Strength and Electrode Length

Modeling Objectives Achieved

- Optimize the AP-DBD reactor in terms of selectivity, deposition rate and product yield using a confining stream
- Examine deposition dynamics with modified T-injection and showerhead (limiting case of repeated confinements)
- Propose an injection head design with spatially uniform flow field of discharged gas using a CFD model
- Couple 1D and 2D fluid models of plasma discharge to examine plasma physics
 - In a decoupled model, time-dependent plasma equations are solved in 1D until periodic steady state is reached. The reaction source of dominant metastables N₂ ($A^3\Sigma_u^+$) is subsequently coupled to the reaction chemistry of the 2D stationary model of the deposition reactor.

Model of Deposition Dynamics

• Incompressible, laminar flow of Newtonian solvent

$$\rho (\mathbf{u} \cdot \nabla) \mathbf{u} = \nabla \cdot \left[-\rho \mathbf{I} + \mu \left(\nabla \mathbf{u} + (\nabla \mathbf{u})^T \right) \right], \quad \rho \nabla \cdot \mathbf{u} = 0$$

• Transport of chemical species (HMDSO precursor, N₂ $(A^3 \Sigma_u^+)$ metastables and [Si₂O] radicals)

$$\nabla \cdot (-D_i \nabla c_i) + \mathbf{u} \cdot \nabla c_i = R_i$$

Main Chemical Reactions

- HMDSO + N₂ $(A^{3}\Sigma_{u}^{+}) \rightarrow [Si_{2}O] + Y_{1}$ (k_g = 4 × 10⁻¹¹ cm⁻³/s, homogeneous reaction)
- ② $[Si_2O] + 3 O \rightarrow Si_2O_4$ (s) +Y₂ (k_s = 1/4 $\gamma c_c v_{th}$, surface reaction, oxidant excess)
- **③** HMDSO + N₂ ($A^3 \Sigma_u^+$) → HMDSO + N₂ (k_q=k_g, parallel quenching reaction)

Model Justification

Justifications of:

- Fluid model: low Knudsen number, $Kn = \lambda/H \sim 10^{-4} \ll 1$, where $\lambda = kT/(\sqrt{2}\pi d^2p) \sim 10^{-7}$ m
- Decoupling: time scale separation between diffusive mass transfer and plasma discharge $\tau_{mass} = D_C/H \sim 1 \text{ s}$ $\gg \tau_{RF} \sim 10^{-4} \text{ s}$
- Decoupling: time scale separation between convective mass transfer and plasma discharge $\tau_{conv} = L/U > 10^{-3} \text{ s} > \tau_{RF}$
- Incompressibility: Mach number $Ma = U/c \sim 10^{-2} \ll 1$, with speed of sound c
- Dimensionality reduction: large geometrical aspect ratio $W \gg H$
- Laminar flow: Reynolds number $Re = UH/\nu \sim 10^2$, where ν is the kinematic viscosity

Outline



2 Reactor Description

3 Optimization of Confinement Strength and Electrode Length

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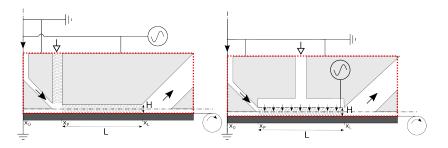
Reactor Design

- Deposition rate directly proportional to wall-normal flux of deposit species.
- Hydrodynamic confinement of precursor near depositing film
 → increase in selectivity and substrate-normal mass flux of
 reaction intermediates (radical species) due to their increased
 near-substrate concentration.
- Angled precusor injection serves to minimize recirculation zones and provide simple, uniform convective flow (Pe \gg 1).
- Injection head located close to substrate to minimize stray deposition and powder formation.
- Exhaust serves to remove by-products (incl. nano-powders) and reactive species. Angled to minimize turbulence (film inhomogeneity).

Design Limitations

- Model is, for the most part, constrained by the condition that the precursor concentration remains below a specified limit everywhere in the plasma zone. Even though relaxing this condition naturally results in increase in deposition rates, it may also induce filamentation due to increased quenching of N₂ metastables by HMDSO.
- At the expense of diluting the stream, the confining flow generates a high concentration layer within the gap cross section, located near the substrate.

Computational Domain – 2D cross-section



- Plasma source: $V_{RF} = 6$ kV, f = 5 kHz, P = 1 W/cm²
- Total gas flow rate $Q(N_2) = 5$ slm
- Precursor concentration $c_{A0} = 50$ ppm
- Confinement strength as a dilution factor $D = 1 f_Q$, where f_Q is fraction of gas flow rate in precursor inlet
- Electrode length $L/H \in (10..100)$, H = 1 mm

Computational Domain – 3D

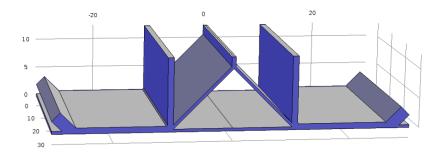


Fig.: A 3D sketch of the reactor for substrate width 3 cm.

Model Description Reactor Description Optimization of Confinement Strength and Electrode Length	Deposition Selectivity Deposition Rate Product Yield Optimal Solutions
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Outline



2 Reactor Description



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Deposition Selectivity Deposition Rate Product Yield Optimal Solutions

Performance Criteria

Defining deposition selectivity S, rate v_N and yield Y_D ,

$$S \equiv \frac{\bar{v}_D - \bar{v}_D^S}{\bar{v}_D + \bar{v}_D^S} \in \langle -1, 1 \rangle,$$
(1)
$$v_N \equiv \frac{\bar{v}_D}{\bar{v}_D(D=0)}, \quad \text{where } \bar{v}_D^{(S)} = \frac{1}{L} \int_{x_P}^{x_L} v_D^{(S)}(x) \, dx,$$
(2)
$$Y_D = \frac{\int_0^H [c_A(x_P, y) - c_A(x_L, y) - c_C(x_L, y)] \, \mathbf{u} \cdot \mathbf{n} \, dy}{\int_0^H c_A(x_P, y) \, \mathbf{u} \cdot \mathbf{n} \, dy},$$
(3)

where c_A and c_P are molar concentrations of precursor and product, respectively.

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Selectivity

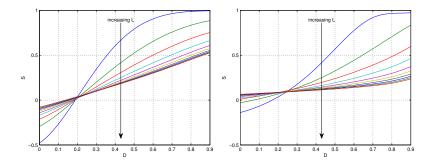


Fig.: The selectivity vs dilution factor. While the confining stream increases selectivity by suppressing stray deposition, its effect diminishes for increasing *L*. Left: T-injection. Right: Showerhead injection.

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Deposition Rate

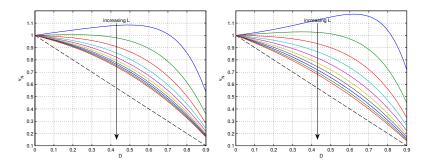


Fig.: The relative deposition rate vs dilution factor. The mass balance is favorable for short deposition regions. Left: T-injection. Right: Showerhead injection. The dashed line denotes an equivalently diluted system without the confining flow, for which $v_N = f_Q$.

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Deposition Rate, Leveling the Playing Field

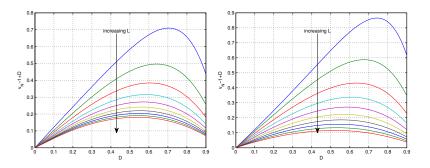


Fig.: Confinement efficiency as the difference between the relative deposition rate and the line $v_N = f_Q$, with the linear v_N dependence representing an equivalently diluted system without the confining flow. Left: T-injection. Right: Showerhead injection.

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Example: Reference Deposition Rate Needed

So that we can: $v_N \rightarrow \bar{v}_D(Q, c_{A0}; D, L) \rightarrow \delta(v_w)$

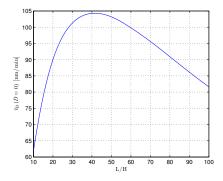


Fig.: The mean-integral deposition rate for given (Q, c_{A0}) without confinement (D=0, reference). For L/H> 40, the additional electrode length provides negligible contribution to the integral.

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Example, Cont'd: Compensatory c'_{A0} Increase

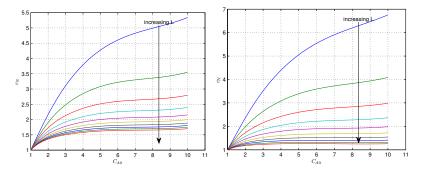


Fig.: The **deposition rate** vs c'_{A0} , with $C_{A0} = c'_{A0}/c_{A0} = 1/f_Q$. Left: T-injection. Right: Showerhead injection.

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Example, Cont'd: Compensatory cA0 Increase

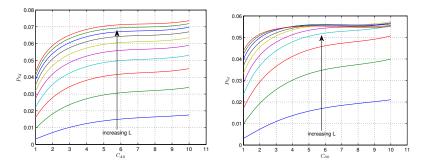


Fig.: The deposition Peclet number $Pe_d = \frac{\delta v_w}{D_{[S_2O]}}$, with $\delta v_w = \bar{v}_D L$ and $D_{[S_i_2O]} = 1.13 \times 10^{-5} \text{ m}^2/\text{s}$. For D = const, Pe_d is thus directly proportional to the **deposited height** $\delta = \frac{1}{v_w} \int_0^L v_D(x) dx$, or the product $\bar{v}_D L$, where $v_w = \text{const}$ is the substrate speed. Left: T-injection. Right: Showerhead injection.

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Product Yield

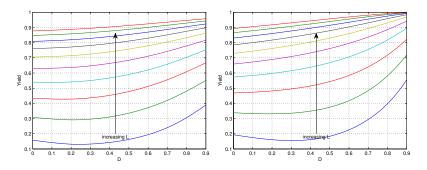


Fig.: Silica yield vs dilution factor. The dependence on *D* is gradually lost for long discharges as the gas residence time becomes sufficient for almost complete conversion of the precursor irrespective of internal re-distribution of flow rates within the reactor. Left: T-injection. Right: Showerhead injection.

Deposition Selectivity Deposition Rate Product Yield **Optimal Solutions**

Vector Optimization

A composite objective function β , based on a linear scalarization

$$\beta = \sum_{i=1}^{3} w_i f_i(\mathbf{x}), \quad \sum_{i=1}^{3} w_i = 1, \quad \mathbf{x}^* = \max_{\mathbf{x} \in \mathbf{X}} \beta(\mathbf{x}), \quad (4)$$

where $\mathbf{f} = (S, v_N, Y_D)$ are, respectively, the individual objective functions, normalized to (0, 1) range and $\mathbf{w} = (w_S, w_V, w_G)$ is a corresponding weight vector. The solution vectors $\mathbf{x} = (D, L)$ are chosen from a set $\mathbf{X} = \mathbf{x} : \{0 \le D < 1, 10 \le L/H \le 100\}$, with the feasible solution denoted by asterisk.

Deposition Selectivity Deposition Rate Product Yield Optimal Solutions

Vector Optimization

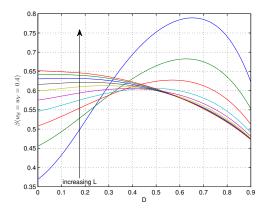


Fig.: For a specific weighting scheme of $w_S = w_V = 0.4$, we obtain $D^* = 0.65$ and $L^*/H = 10$, based on the objective function $\beta(D, L)$. T-injection.

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Optimal Solutions

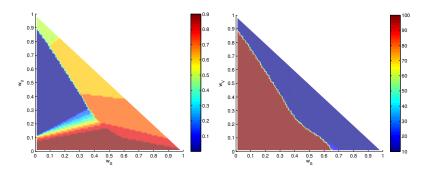


Fig.: Optimal solutions with selectivity, deposition rate and **product yield** as component objective functions. Left: Optimal dilution factor $D^* = D^*(w_S, w_W)$. Right: Optimal electrode length $L^* = L^*(w_S, w_W)$.

Deposition Selectivity Deposition Rate Product Yield **Optimal Solutions**

Sensitivity of Optimal Solutions to the Choice of Criteria

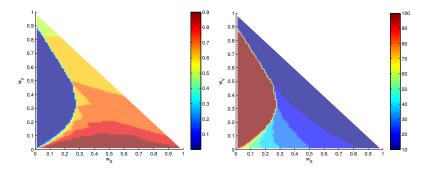


Fig.: Optimal solutions with selectivity, deposition rate and **precursor conversion** $\gamma_A = 1 - \frac{\int_0^H c_A(x_L, y) \mathbf{u} \cdot \mathbf{n} \, dy}{\int_0^H c_A(x_F, y) \mathbf{u} \cdot \mathbf{n} \, dy}$ as component objective functions. Left: Optimal dilution factor $D^* = D^*(w_S, w_W)$. Right: Optimal electrode length $L^* = L^*(w_S, w_W)$.

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Optimization of Confinement Strength and Electrode Length	0

Deposition Selectivity Deposition Rate Product Yield **Optimal Solutions**

Conclusions

- **Selectivity** increases with *D* as the confining stream reduces stray deposition. The effect is, however, reduced for longer discharges due to interfacial diffusion which equalizes the cross-sectional concentration profile. T-injection preferred.
- Without compensatory increase in precursor concentration, the confinement increases **deposition rate** only for small *L*. For $L > L_{tres}$, the preferential deposition on the substrate (mass gain due to limited stray deposition) is unable to compensate for the mass loss of the precursor due to dilution. Showerhead preferred.
- The dependence of **product yield** on *D* is gradually lost for long discharges as the gas residence time becomes sufficient for almost complete conversion of the precursor irrespective of internal re-distribution of flow rates within the reactor.

Deposition Selectivity Deposition Rate Product Yield **Optimal Solutions**

Conclusions (cont'd)

The domains of optimal solutions are dependent on the choice of optimization criteria. E.g. product yield criterion is more realistic, as it considers not only the precursor conversion (A→C), but also the surface deposition of the reaction intermediate (C→D), which can only occur over an additional diffusion length. We do not, however, consider powder formation due to unfavorable bulk reactions, which can be a limiting factor for long deposition chambers with long gas residence times. In such case the reactant conversion as an optimization criterion may be preferable.